Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/785,543	MCLLWAINE ET AL.		
Examiner	Art Unit		
Ouveb H. Nauven	2614		

	SEARCHED				
Class	Subclass	Date	Examiner		
379	265.01 265.02 265.05 266.07	8/2/06	QN		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			1	

(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
Searched: East, USPAT, USPGPub	8/2/06	QN
Inventor searched through PALM database	8/2/06	QN
- 1 - 1		
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